



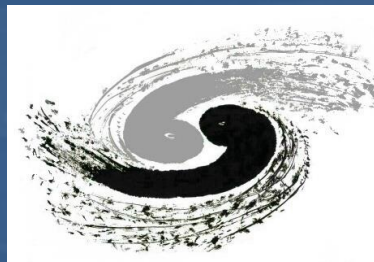
BERKELEY LAB
LAWRENCE BERKELEY NATIONAL LABORATORY



ITSDAQ Tutorial

Kaili Zhang, Karol Krizka, Timon Heim, Sandra Ciocio

06/26/20



Outline

- Hardware Environment
 - . ABCStar Module, Test box
- Software Environment
 - . ITSDAQ
- How to run the module test

ITk Strips Data AcQquisition

ABC module paper:

<https://drive.google.com/file/d/17gO3LLPXOHtYzvcszJuyqWYmmrwEdjvt/view?usp=sharing>

General introduction for strips module

ITSDAQ Documentation:

<https://atlas-strips-itsdaq.web.cern.ch/index.html>

<https://twiki.cern.ch/twiki/bin/viewauth/Atlas/StripsUpgradeDAQ>

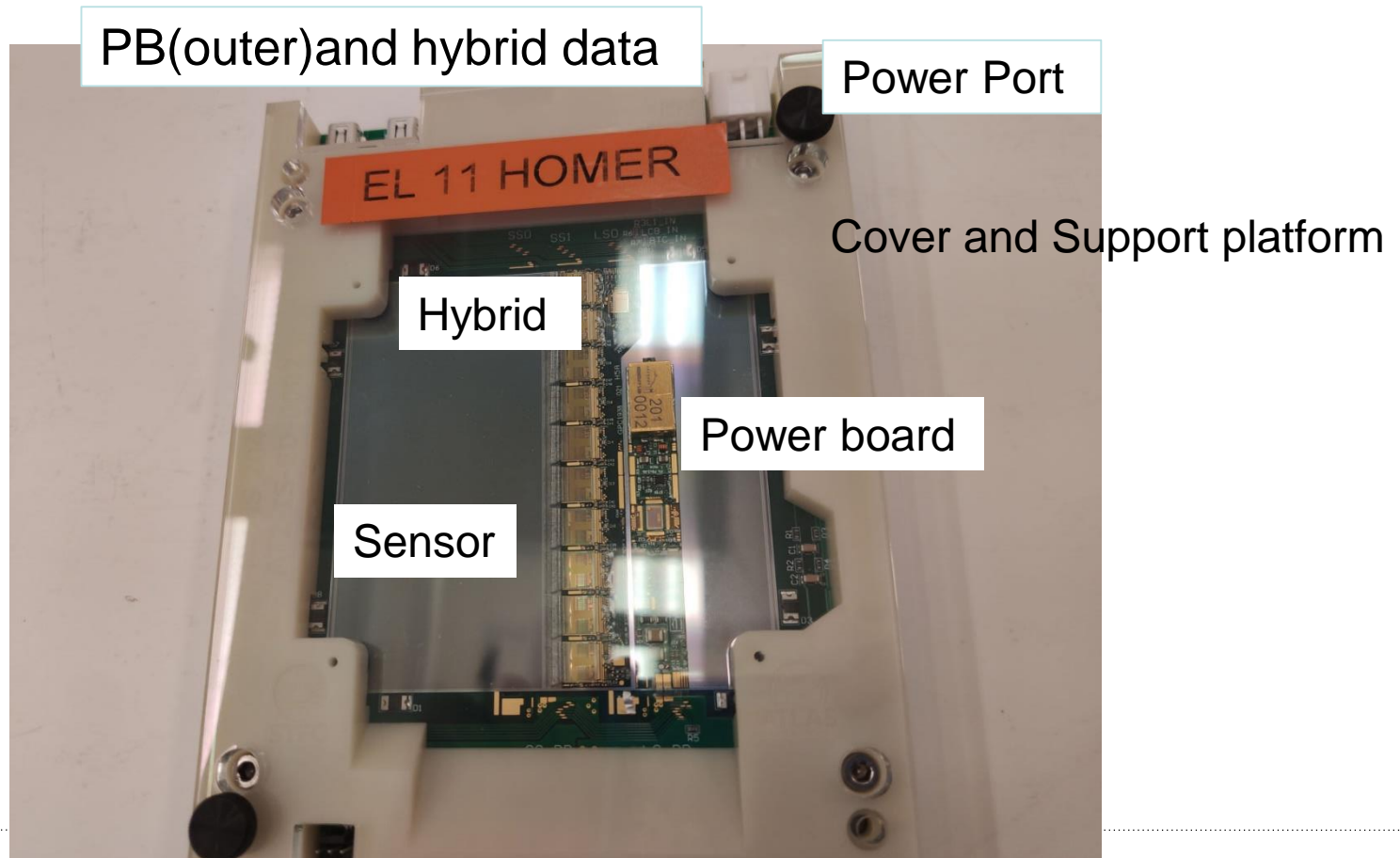
Gitlab:

<https://gitlab.cern.ch/atlas-itk-strips-daq/itsdaq-sw>

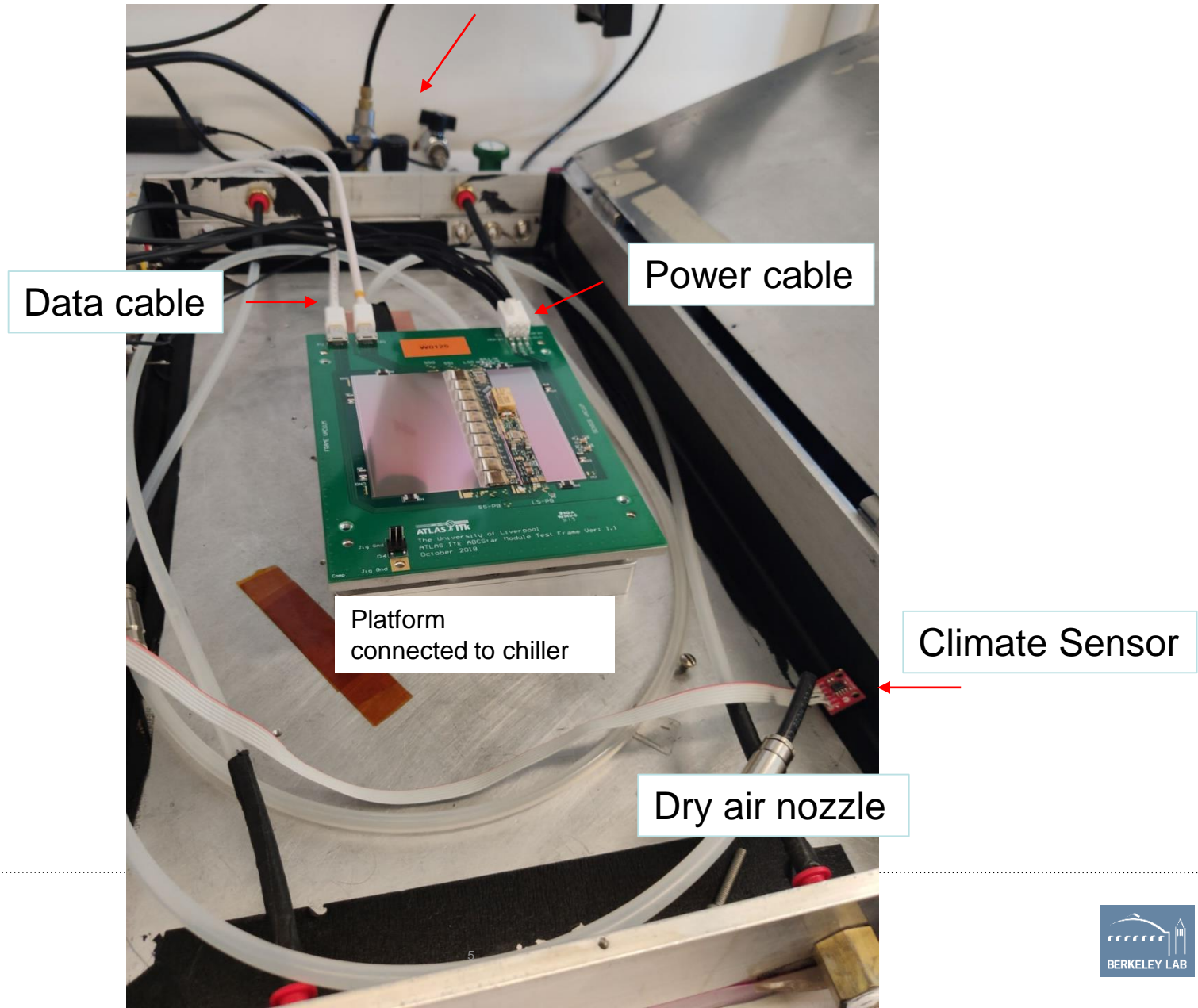
(Need to sign in [usatlas-itk-strips-technical](#) e-group first)

Our module test environment

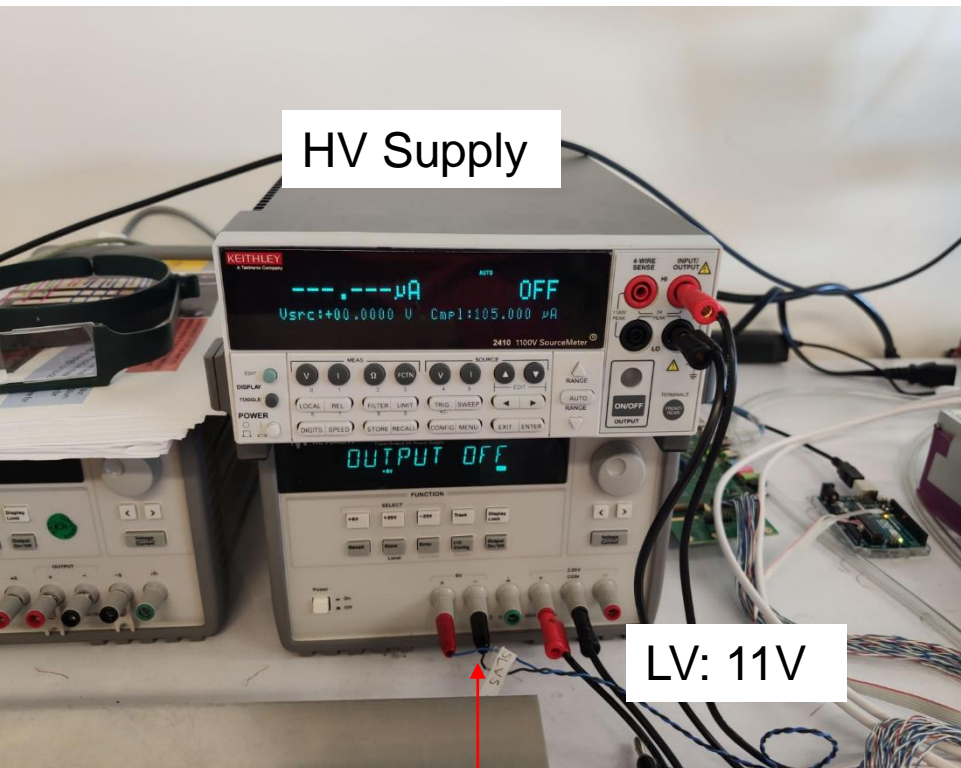
On one barrel Long Strip module, we have 10 ABCstar chips, 1 HCCstar chip, and 2560 readout channels.



Test box



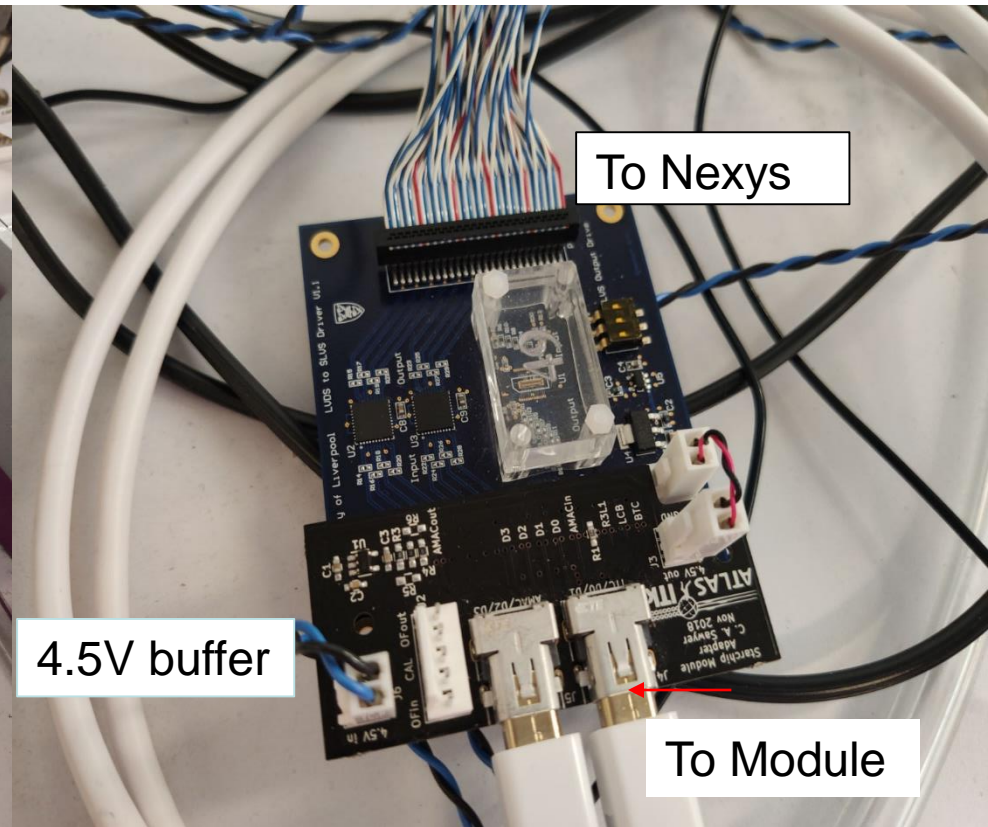
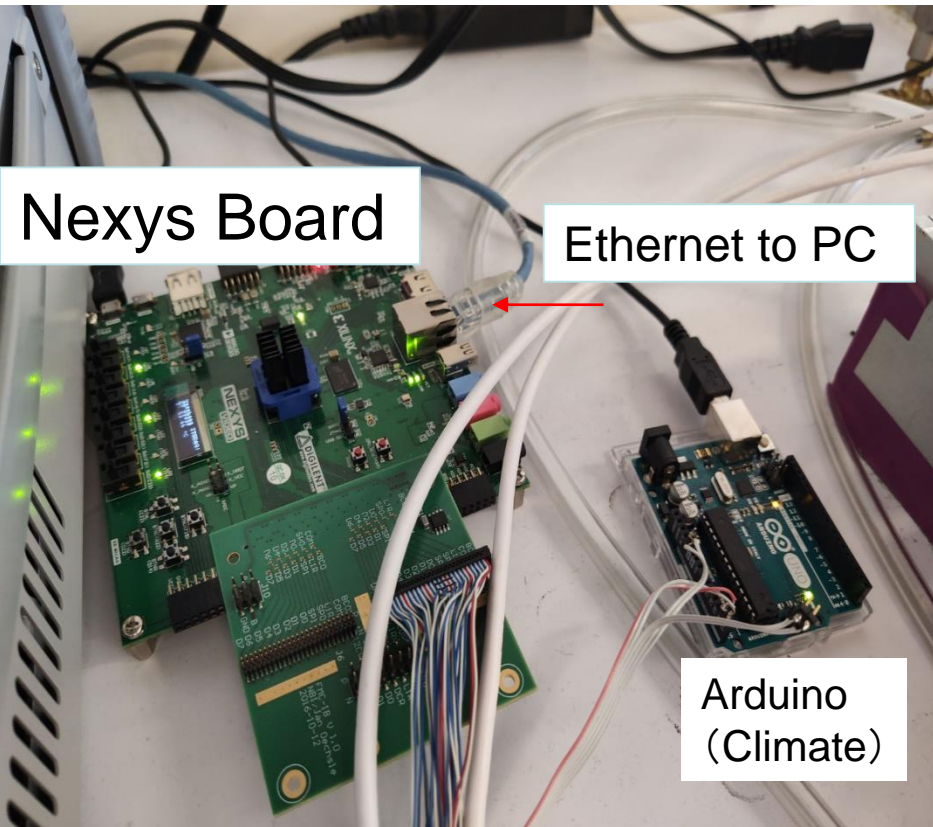
Power and temperature supply



SLVS buffer: 4.5V

Data Cable Connection

PC $\xrightarrow{\text{RJ45}}$ Nexys \rightarrow SLVS Adpter $\xrightarrow{\text{MiniDP}}$ Module



Hybrid panel and module test have different connection and different Nexys firmware.

Software preparation

- Install and compile ITSDAQ / Update to latest;
 - Instruction could be found in [here](#)
- Use latest firmware for Nexys.
 - Current one is [nexysv_itsdaq_vb437_FIB_STAR.bit](#)
 - For star module test, always with FIB_STAR
- Prepare module configuration files
 - Set vars like SCTDAQ_VAR and WorkDir;
 - Modify st_system_config.dat
- Open Arduino to monitor

Done in
setup_fpga.sh

Done in
continue_previous_test.sh

Commands on current Strips PC

Terminal 1:

```
cd ITk  
  
./setup_fpga.sh  
  
source continue_previous_test.sh  
  
cd ./RUNITSDAQ.sh  
  
//(Type your name, 2 letters)
```

Terminal 2: (Set HV)

```
cd ITk/IVScan  
  
python Console.py  
  
set_comp -v 50  
  
iv_scan -v -350 -t 5
```

setup_fpga.sh listed the Nexys firmware you want.

continue_previous_test.sh:

-SCTDAQ_VAR	working dir
-SCTDAQ_ROOT	ITSDAQ dir

Open ITSDAQ

Open another terminal for HV control.

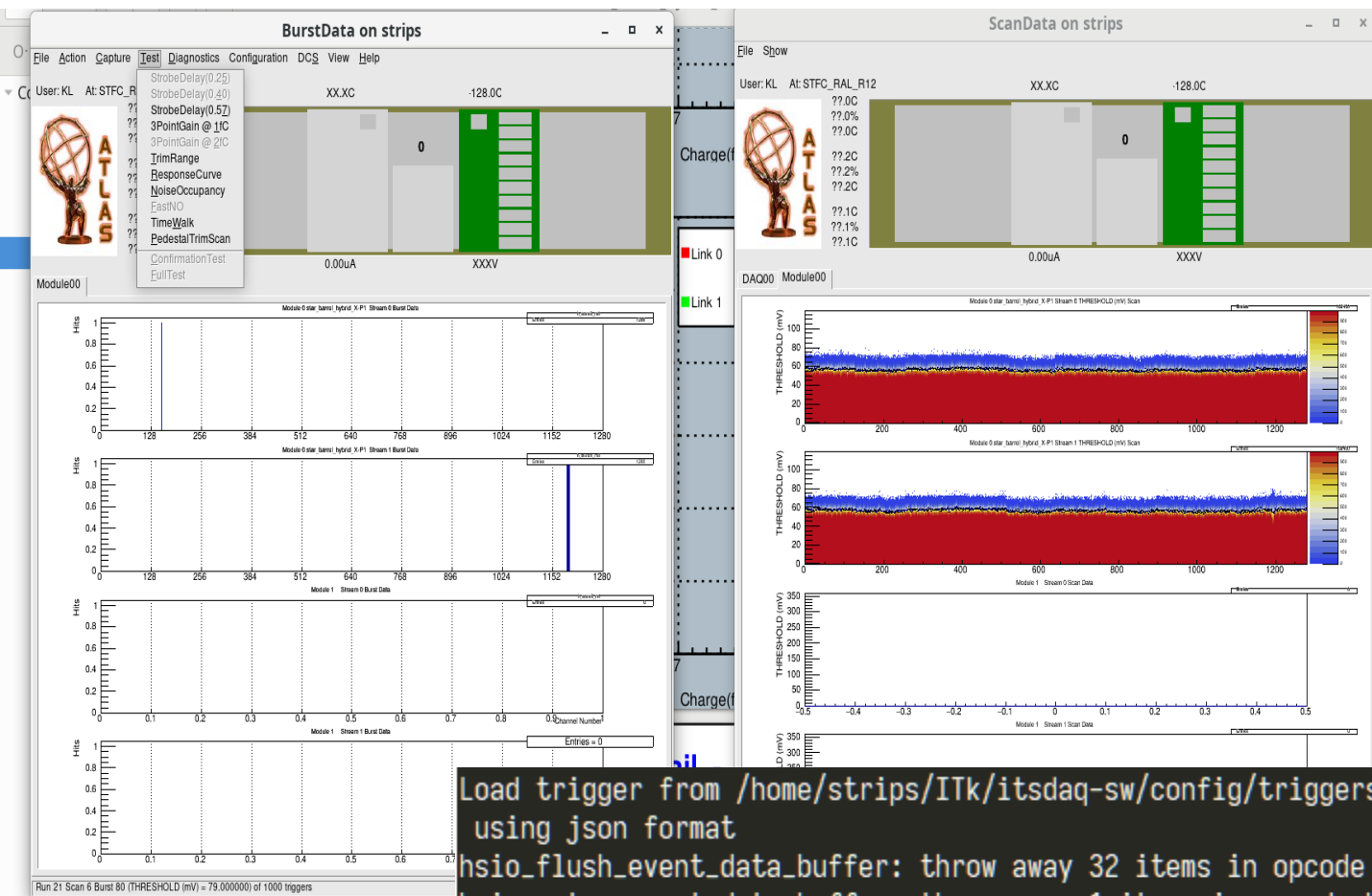
Set HV compliance current to $50\mu A$.

Ramp HV from 0V to -350V.

(Always negative!)

Every 5s, steps 10V.

Software interface for ITSDAQ



In terminal:

```
Load trigger from /home/strips/ITk/itsdaq-sw/config/triggers/abc_star/load_fuse_id.json
using json format
hsio_flush_event_data_buffer: throw away 32 items in opcode buffer
hsio_setup_event_data_buffer: throw away 1 items in opcode buffer
hsio_flush_event_data_buffer: throw away 23 items in opcode buffer
1: (15) 9 8 7 6 5 4 3 2 1 0
ST() ...ready for action!
Run number is 26.
ST [1] █
```

ITSDAQ Commands: AMAC

```
./RUNITSDAQ.sh  
(Now in ITSDAQ Terminal)  
(Type name for DB and type 1)  
.L AMACv2.cpp  
AMACv2_setID(0,0,0)  
AMACv2_setID(0,0,0)  
AMACv2_DCDC(0, 1, 0)  
val = 0x00077700 //HV enabled, LDOs enabled  
AMACv2_writeReg(0,40,val,0)  
AMACv2_writeReg(0,41,val,0)  
val = 0x00010100 //Release reset on HCC  
AMACv2_writeReg(0, 46, val, 0)  
AMACv2_writeReg(0, 47, val, 0)  
e->Restart()
```

Load commands for AMAC control.

Set the comm ID of the AMAC, **twice**.

Turn on DCDC.

(LV current changes)

Enable HV and LDOs. Now Hybrid is powered.

(LV current changes)

Release HCC reset

(LV current changes)

Restart

Register [map](#) for AMAC(Autonomous Monitor And Control)
Need the group [atlas-itk-strips-asics](#) permission

ITSDAQ Commands: HCC

(Followed by AMAC Commands)

```
hcc_star_reg_write(16,4)
```

```
hcc_star_reg_write(17,0xf0004223) //HCC ID varies.
```

```
abc_star_fast_command(2,2)
```

```
abc_star_fast_command(3,0)
```

```
e->ExecuteConfigs()
```

```
abc_star_fast_command(2,2)
```

```
abc_star_fast_command(3,0)
```

```
e->ExecuteConfigs()
```

Transfer Fuse ID to address register

Set new HCC comm ID.

Reset config **twice**

Here the HCC comm ID is dumped from the previous Hybrid test.

//Transfer Fuse ID to address register

```
hcc_star_reg_write(16,4)
```

//Dump register

```
st_dump_chip_registers()
```

Get the ID In address 17.

Start work

- Turn on
 - dry air and chiller. Monitored by Arduino.
 - HV and LV. Output off.
- Settle module down to the box, connect all the wires
 - Wait for humidity and temperature below 25% and 20° .
- Output on, LV and HV.
 - 6V output set to 4.5V
 - 25V output set to 11V
 - (After ITSDAQ enabled HV)
 - set HV compliance current to $50\mu A$. Volts ramp to -350V.
- Open ITSDAQ

Chiller set to 15° but there would be difference between chiller and Arduino sensor.

Structure of Workdir

config
data
etc
hsio
ps
results
timers

config/st_system_config.dat: Overall configuration

(See [sysconfig](#))

config/star_barrel_hybrid_X-P1.*: Hybrid configuration.

Name set in st_system_config.dat

(See [abcstar config](#))

Test results storage:

results: plain text

data: root file

ps: pdf plots

Results stored by run number and scan number.

Each root file, strunX_X.root, corresponds to one inject charge scan.

One 3PG test would have 3 output files for 0.5fc, 1fc and 1.5fc.

Root file structure.

Histograms could be found directly.

Scan 0 and Scan 1 are the 2 sides of ABCchips.

Each 1280.

```
root [1] .ls
TFile**      strun20_7.root
TFile*       strun20_7.root
KEY: TObject Time;1 Collectable string class
KEY: TObject Place;1 Collectable string class
KEY: TObject Host;1 Collectable string class
KEY: TObject User;1 Collectable string class
KEY: TObject ModuleName;1 Collectable string class
KEY: TObject DUT;1 Collectable string class
KEY: TH2F h_scan0;1 Module 0 star_barrel_hybrid_X-P1 Stream 0 THRESHOLD (mV) Scan
KEY: TH2F h_scan1;1 Module 0 star_barrel_hybrid_X-P1 Stream 1 THRESHOLD (mV) Scan
KEY: TH1F h_mean0;1 Module 0 star_barrel_hybrid_X-P1 Stream 0 Fitted Mean
KEY: TH1F h_mean1;1 Module 0 star_barrel_hybrid_X-P1 Stream 1 Fitted Mean
KEY: TH1F h_sigma0;1 Module 0 star_barrel_hybrid_X-P1 Stream 0 Fitted Sigma
KEY: TH1F h_sigma1;1 Module 0 star_barrel_hybrid_X-P1 Stream 1 Fitted Sigma
KEY: TH1S h_code0;1 Module 0 star_barrel_hybrid_X-P1 Stream 0 Fit Code
KEY: TH1S h_code1;1 Module 0 star_barrel_hybrid_X-P1 Stream 1 Fit Code
KEY: TH1F h_chisq0;1 Module 0 star_barrel_hybrid_X-P1 Stream 0 Chisq/NDF
KEY: TH1F h_chisq1;1 Module 0 star_barrel_hybrid_X-P1 Stream 1 Chisq/NDF
KEY: TH1F h_prob0;1 Module 0 star_barrel_hybrid_X-P1 Stream 0 Chisq Prob
KEY: TH1F h_prob1;1 Module 0 star_barrel_hybrid_X-P1 Stream 1 Chisq Prob
KEY: TH1F h_fom0;1 Module 0 star_barrel_hybrid_X-P1 Stream 0 Figure of Merit
KEY: TH1F h_fom1;1 Module 0 star_barrel_hybrid_X-P1 Stream 1 Figure of Merit
KEY: TH2F h_hitsPerLink0;1 Module 0 star_barrel_hybrid_X-P1 Stream 0 THRESHOLD (mV) Hits Per Link
KEY: TH2F h_hitsPerLink1;1 Module 0 star_barrel_hybrid_X-P1 Stream 1 THRESHOLD (mV) Hits Per Link
KEY: TH1F h_cluster0;1 Module 0 star_barrel_hybrid_X-P1 Stream 0 Cluster Size
KEY: TH1F h_cluster1;1 Module 0 star_barrel_hybrid_X-P1 Stream 1 Cluster Size
KEY: TH2F h_corr;1 Module 0 star_barrel_hybrid_X-P1 Correlated Hits
KEY: TH1F h_scan_tsent;1 Triggers Sent
KEY: TH1F h_scan_evtcnt;1 DAQ card 0 Events Decoded
KEY: TH1F h_scan_errcnt;1 DAQ card 0 Decoding Errors
KEY: TH1F h_scan_tocnt;1 DAQ card 0 Timeouts
KEY: TH1F h_scan_xecnt;1 DAQ card 0 Cntrl Errors
KEY: TObject schema_version;1 Collectable string class
KEY: TDirectoryFile system_info;1 system_info
KEY: TDirectoryFile scan_info;1 scan_info
KEY: TDirectoryFile scan_points;1 scan_points
KEY: TDirectoryFile configuration;1 configuration
```

Test step

Always run PedstralTrimScan first and StrobeDelay first.

Then:

- 3 Point Gain and Response VS Channel
 - Use manual script to get the S-Curves of RC test.
- Noise Occupancy
- TrimRange

<https://atlas-strips-itsdaq.web.cern.ch/tests.html>

Definitions for those tests.

More information could be found in Twiki and Module paper.

Terminal output for one scan

Module 0 star_barrel_hybrid_X-P1 THRESHOLD (mV) scan from 5 to 255 in steps of 1

Number of active channels 2560

Fit Results for chisq fit

	Mean	Sigma	Chisq	FOM	Prob	nGood	nBad
Chip 0	50.239	3.68	0.7131	2.166	0.7996	128	0
Chip 1	47.84	3.529	0.7071	0.2001	0.8175	128	0
Chip 2	49.8	3.742	0.7134	0.4578	0.8304	128	0
Chip 3	50.694	3.652	0.6714	0.3638	0.8479	128	0
Chip 4	49.339	3.43	0.6442	1.776	0.872	128	0
Chip 5	48.518	3.507	0.7353	0.2026	0.7864	128	0
Chip 6	47.715	3.51	0.7569	0.2295	0.7696	128	0
Chip 7	48.591	3.603	0.7665	0.3638	0.7712	128	0
Chip 8	46.745	3.517	0.732	1.038	0.8074	128	0
Chip 9	48.54	3.586	0.7034	12.14	0.8235	128	0
Evens 48.802	3.576	0.7143	1.894	0.8126	1280	0	
Chip 0	49.828	3.504	0.7219	0.3069	0.8038	128	0
Chip 1	48.197	3.341	0.6466	0.4462	0.8568	128	0
Chip 2	49.917	3.527	0.6717	0.3339	0.8369	128	0
Chip 3	50.08	3.438	0.6385	2.211	0.8799	128	0
Chip 4	48.808	3.203	0.6593	0.6087	0.8336	128	0
Chip 5	49.114	3.21	0.6755	0.3132	0.8413	128	0
Chip 6	48.078	3.219	0.6469	0.1136	0.8608	128	0
Chip 7	48.766	3.407	0.66	1.191	0.8531	128	0
Chip 8	47.166	3.376	0.7092	0.6601	0.8114	128	0
Chip 9	49.061	3.672	0.6646	0.6595	0.8428	128	0
Odds 48.901	3.39	0.6694	0.6844	0.842	1280	0	
Overall	48.852	3.483	0.6919	1.289	0.8273	2560	0

Dead Channels
would show up here.

Laurence Boccolini dit "Vous etes le maillon faible. Au revoir!!"

Strobe Delay Plot

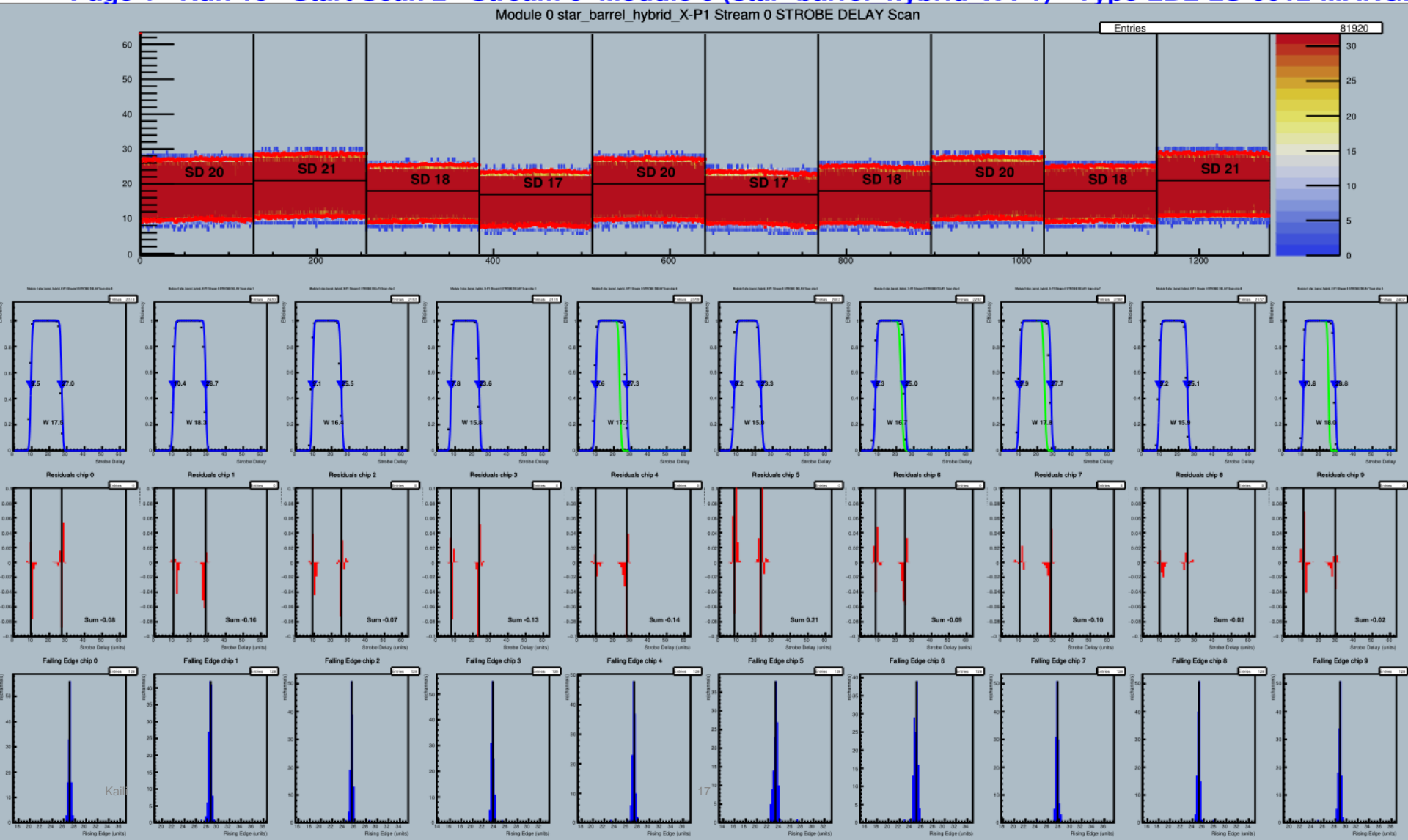
Default: set to 57%.

The expected result is a top hat like plot which can be analyzed to find the rising edge and falling edge.

The appropriate strobe delay is chosen as a fraction along the flat top.

ATLAS SCT Module Test: Strobe Delay - Mon Jun 8 10:37:22 2020 - STFC_RAL_R12 - SD fraction 0.5

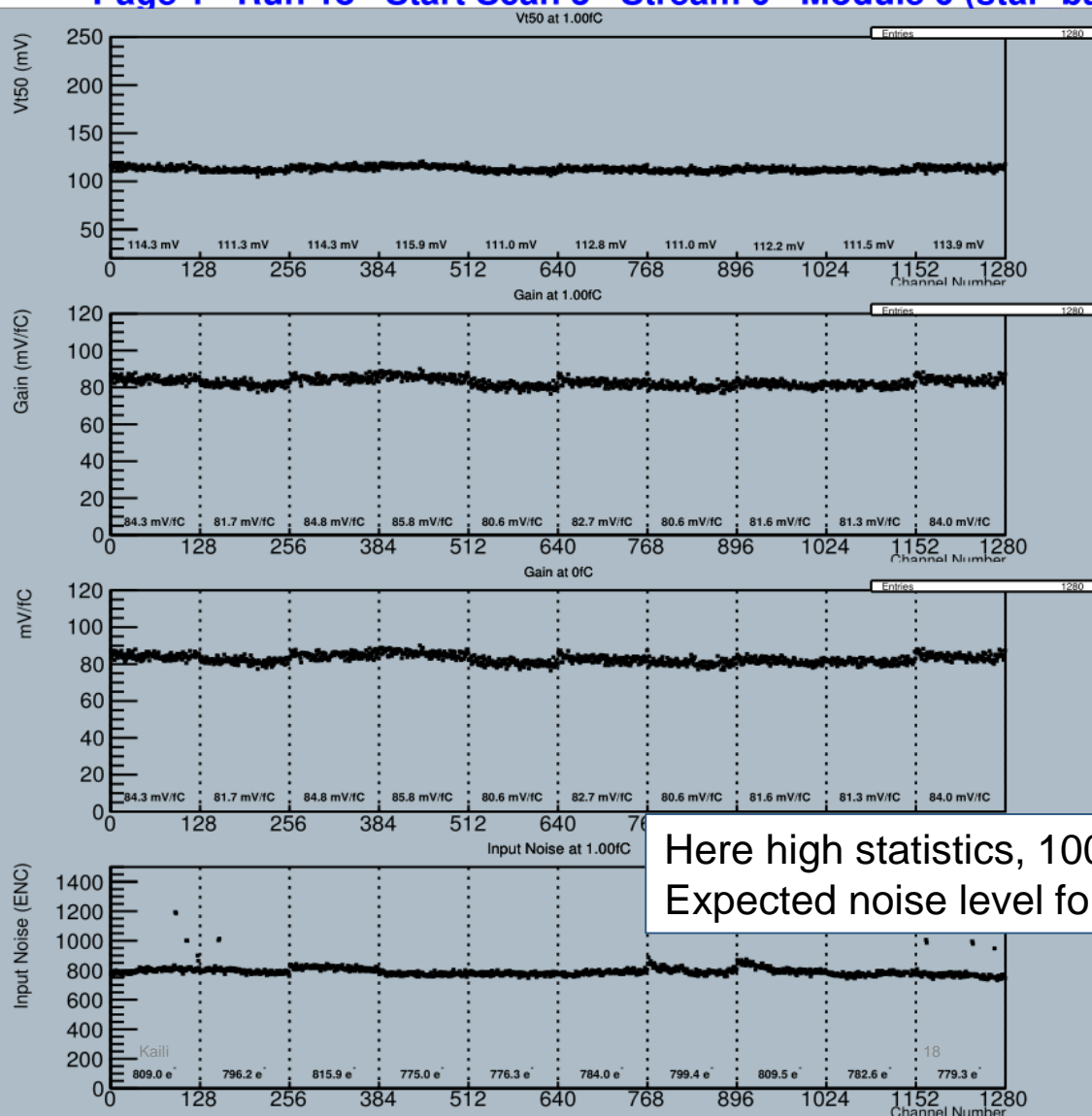
Page 1 Run 18 Start Scan 2 Stream 0 Module 0 (star barrel hybrid X-P1) - Type LBL-LS-0012-MARG



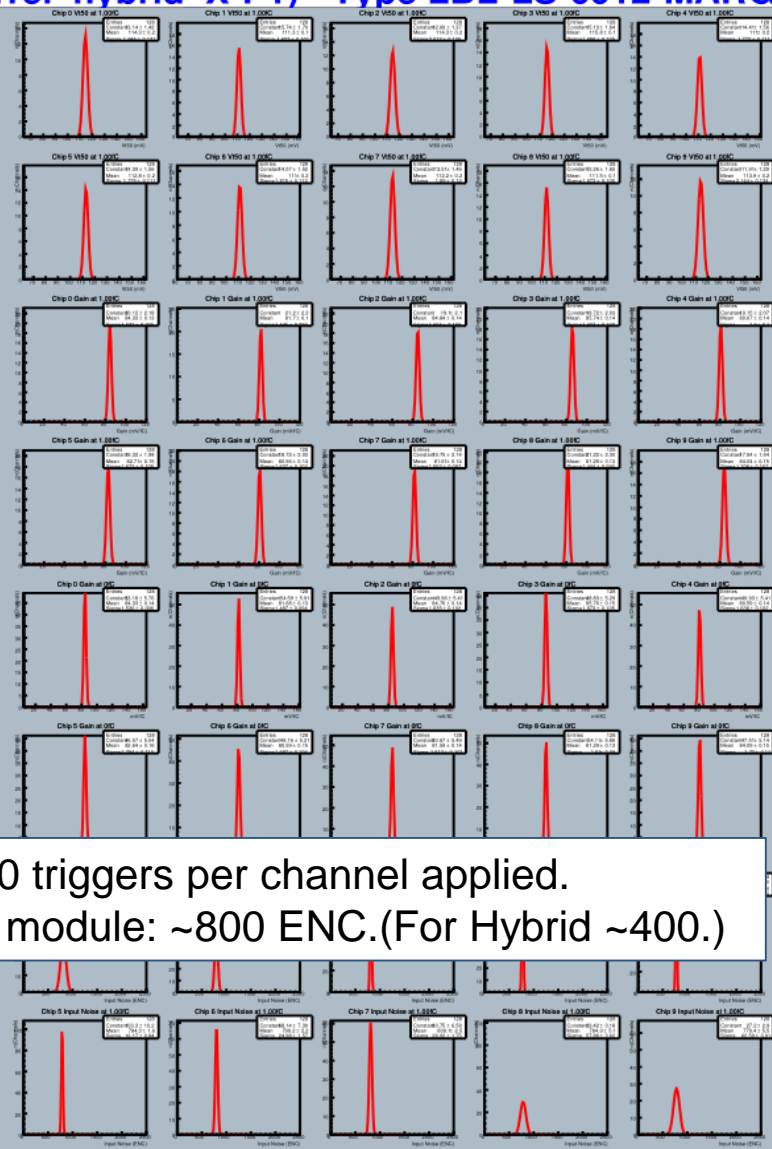
3PG / Response vs. Channel Result

ATLAS ITk Test: Response vs. Channel - Mon Jun 8 10:38:56 2020 - STFC_RAL_R12

Page 1 Run 18 Start Scan 3 Stream 0 Module 0 (star barrel hybrid X-P1) - Type LBL-LS-0012-MARG



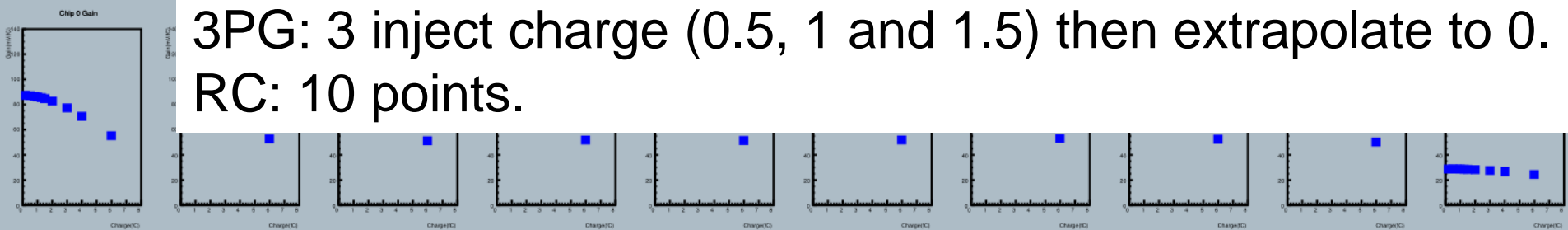
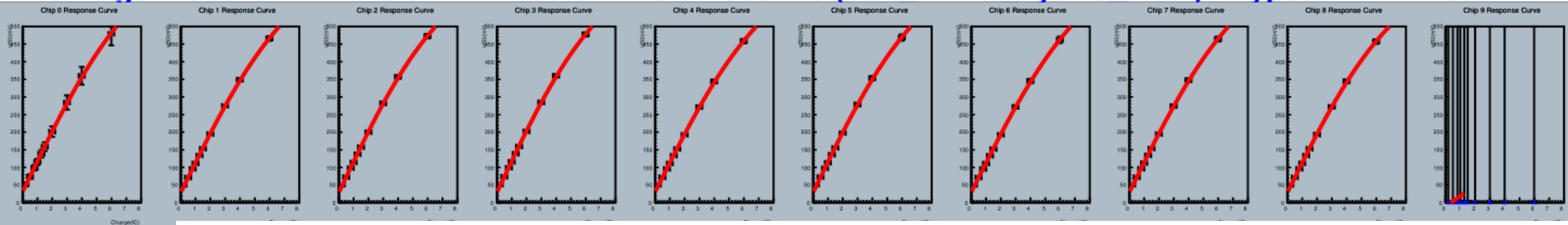
Here high statistics, 1000 triggers per channel applied.
Expected noise level for module: ~800 ENC.(For Hybrid ~400.)



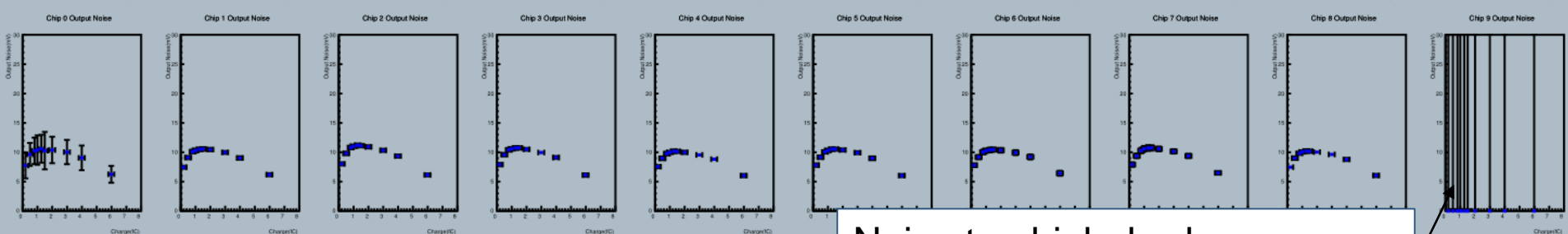
3PG / Response vs. Channel Result(2)

ATLAS ITk Test: Response Curve - Mon Jun 8 10:09:24 2020 - STFC_RAL_R12

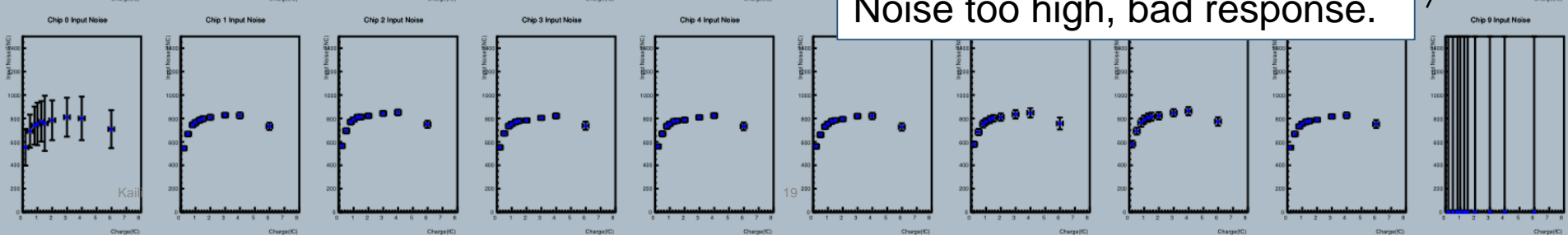
Page 2 Run 17 Start Scan 15 Stream 0 Module 0 (star barrel hybrid X-P1) - Type LBL-LS-0012-MAR



3PG: 3 inject charge (0.5, 1 and 1.5) then extrapolate to 0.
RC: 10 points.



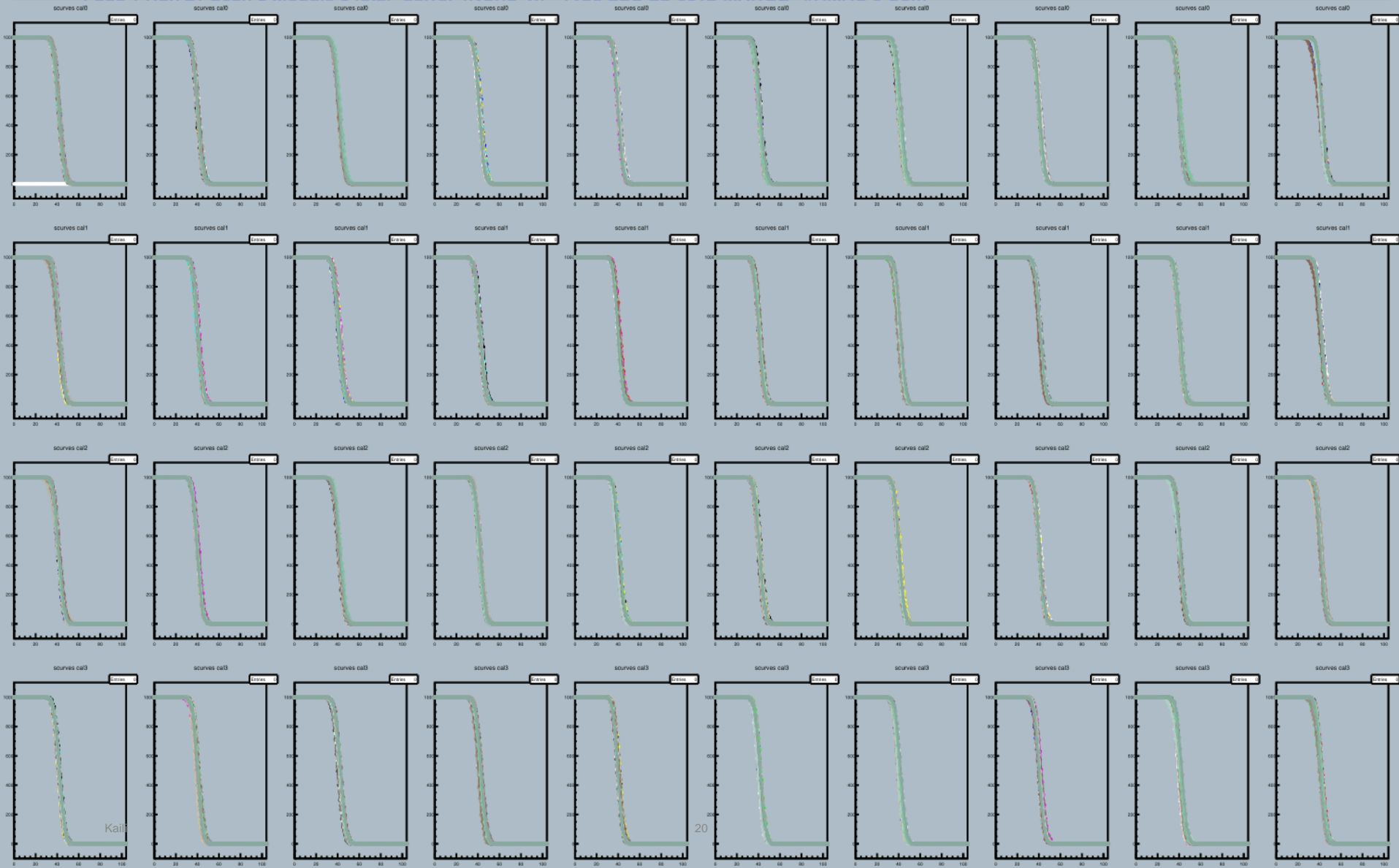
Noise too high, bad response.



RC test S-Curve

Here list $32 \times 10 \times 4 = 1280$ channels

ATLAS Strips Noise Occupancy S-Curves - Tue Jun 16 09:56:18 2020 - STFC_RAL_R12
Page 1 Run 21 Scan 5 Module 0 (star_barrel_hybrid_X) - Type LBL-LS-0012-MARGE #AMAC 0 Com

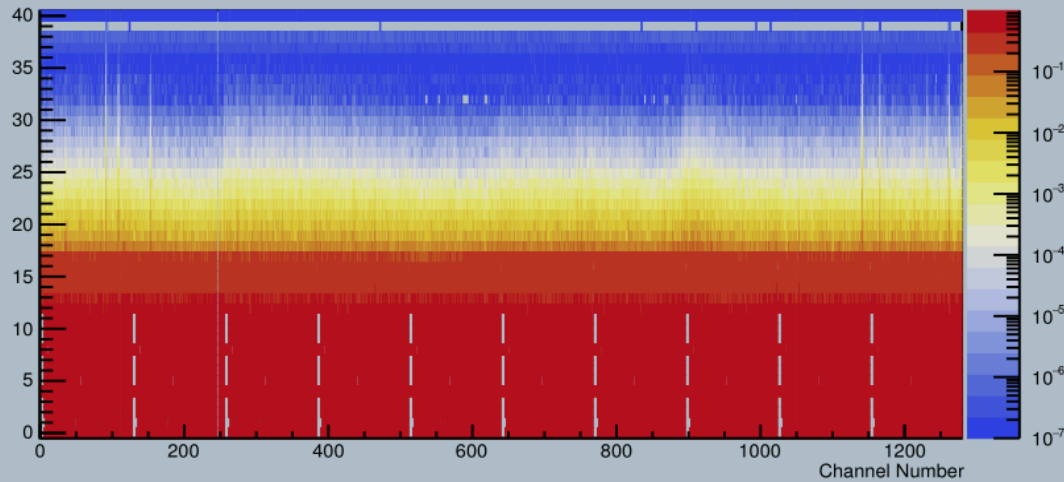


Noise Occupancy

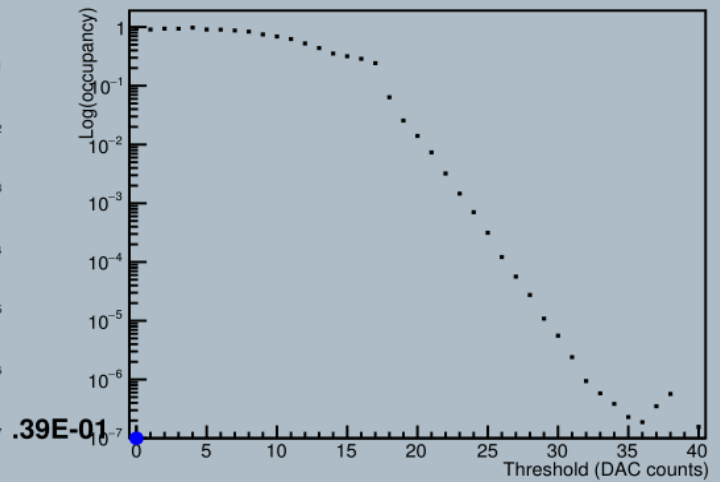
ATLAS Strips Noise Occupancy - log scale - Mon Jun 8 10:01:11 2020 - STFC_RAL_R12

Page 1 Run 17 Scan 8 Module 0 (star barrel hybrid X-P1) - Type LBL-LS-0012-MARGE #AMAC 0 Co

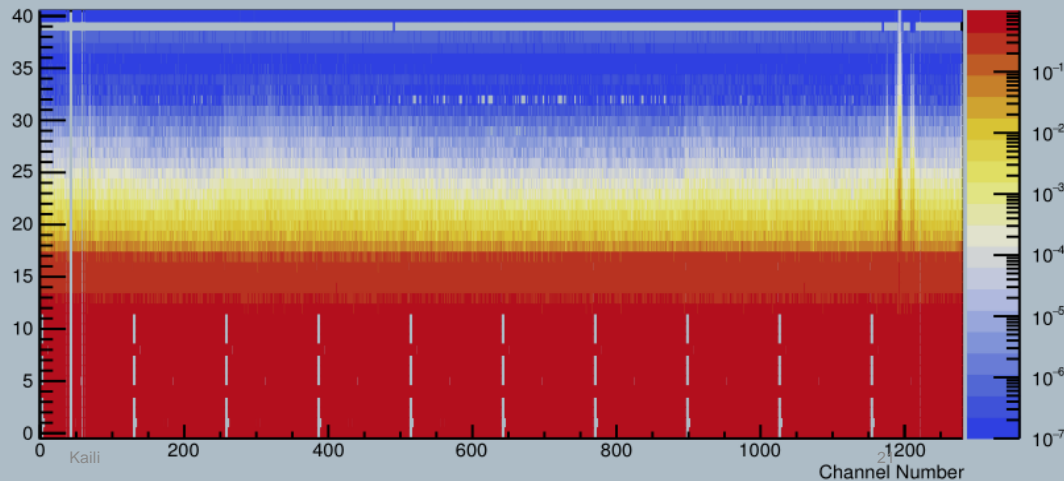
Evans Module 0 star_barrel_hybrid_X-P1 Occupancy Data



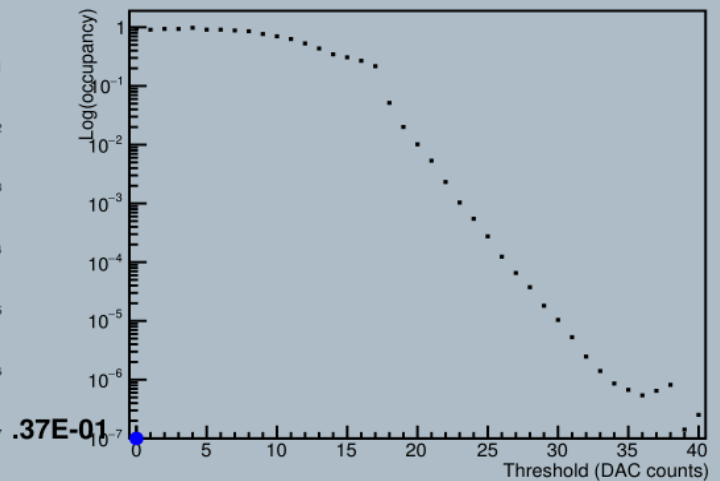
Evans Module 0 star_barrel_hybrid_X-P1 Occupancy Data



Odds Module 0 star_barrel_hybrid_X-P1 Occupancy Data



Odds Module 0 star_barrel_hybrid_X-P1 Occupancy Data



Finish test.....

- Ramp HV back to 0V. (**Important!**)
 - `iv_scan -v 0 -t 5`
- Turn off LV, HV.
- Disconnect the module.
- Exit HV Console and ITSDAQ.
- Switch off FPGA board.
- Turn off chiller, and dry air.

Useful links

ABC module paper:

<https://drive.google.com/file/d/17gO3LLPXOHtYzvcszJuyqWYmmrwEdjvt/view?usp=sharing>

ITSDAQ Documentation:

<https://atlas-strips-itsdaq.web.cern.ch/index.html>

<https://twiki.cern.ch/twiki/bin/viewauth/Atlas/StripsUpgradeDAQ>

Gitlab:

<https://gitlab.cern.ch/atlas-itk-strips-daq/itsdaq-sw>

(Need to sign in [usatlas-itk-strips-technical](#) e-group first)

Useful links

Twiki test page

<https://twiki.cern.ch/twiki/bin/viewauth/Atlas/ABCStarHybridModuleTests>

<https://twiki.cern.ch/twiki/bin/view/Atlas/ITkStrips>

One old/outdated version module test document:

<https://docs.google.com/document/d/1Ep9Gbrr1ILEOma32GRhq-TWVMqyKIbcgtH4sQRugpY4/edit?usp=sharing>

Firmware list

<http://www.hep.ucl.ac.uk/~warren/upgrade/firmware/>

AMAC Register map

https://gitlab.cern.ch/atlas-itkstrasic-group/AMAC/-/blob/master/doc/v2a/AMAC_v2a_Registers-20200313.pdf

Backup

Concepts and definitions you may need on tests

Strobe delay

This is an analogue test, looking at strip data.

- When injecting charge into the front-end of the chip, the pulse can be delayed with respect to the system clock.
- This test scans over the possible delay values while injecting a large charge.
- The expected result is a top hat like plot which can be analysed to find the rising edge and falling edge.
- The appropriate strobe delay is chosen as a fraction along the flat top.

NB: the strobe delay test is typically run before any other charge injection tests.

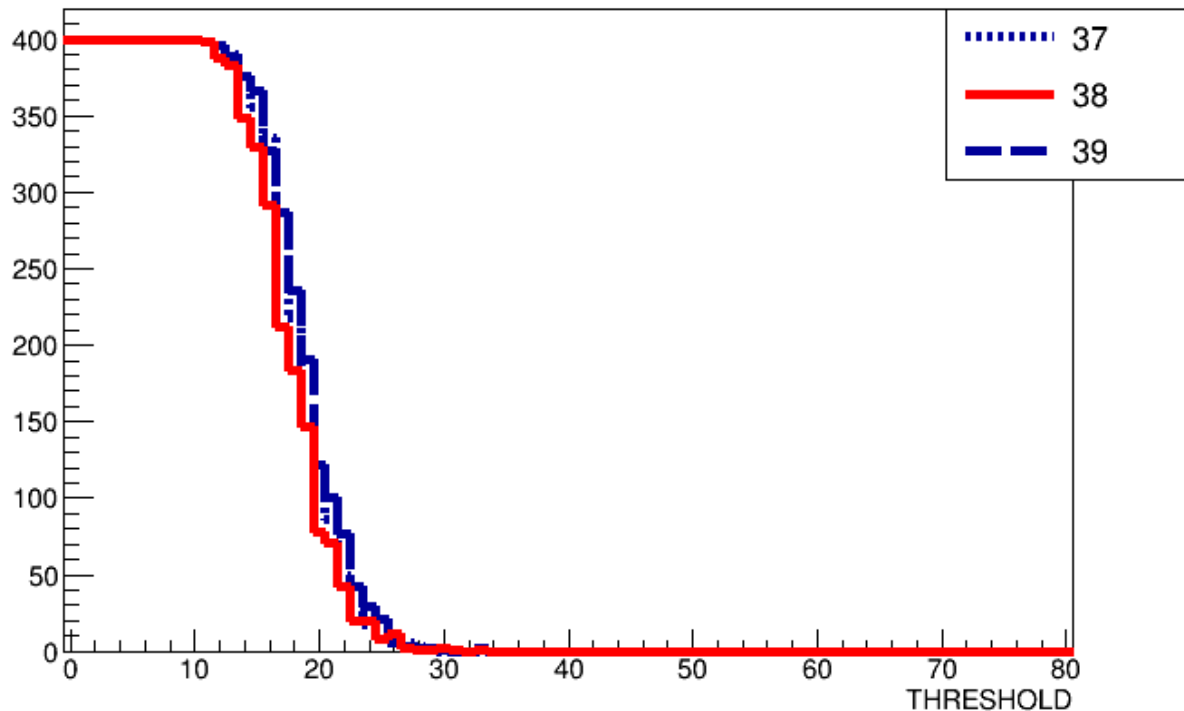
Response Curve (including three point gain)

The response curve is used to measure the response of the front end (in mV or DAC counts) to the injection of a calibration charge.

- This is done by carrying out a series of scans over the threshold DAC.
- For each scan, a different charge is injected into the front-end (3 charges for the three point gain, more, typically 10, for the response curve).
- The output is an S-curve for each channel for each charge.
- The analysis proceeds by fitting the S-curve to find the median threshold (a.k.a. vt50, threshold voltage for 50%) and standard deviation (output noise) for each charge. (see next slide)
- A fit is made of these values to a straight line (for the 3-point gain) or an exponential (for the response curve).
- The chip gain is the gradient of this slope, and the input noise is derived from the output noise at a particular charge by dividing by the gain. The noise is often quoted in electrons, equivalent to the charge of the noise.

S-Curve: For one channel

Module 0 star_barrel_hybrid_X-P1 Stream 0 THRESHOLD (mV) Scan



Noisewidth:
FWHM of the slope.

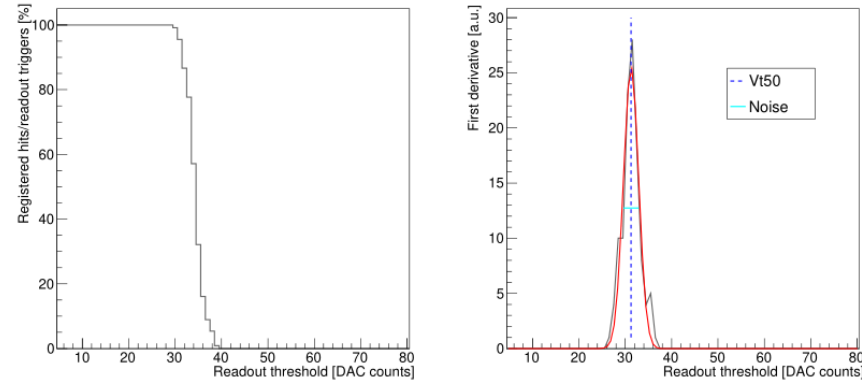
Normalized noise
level, $ENC =$
 $\text{Noisewidth} / \text{Gain}.$

X Axis: Readout threshold [DAC counts]

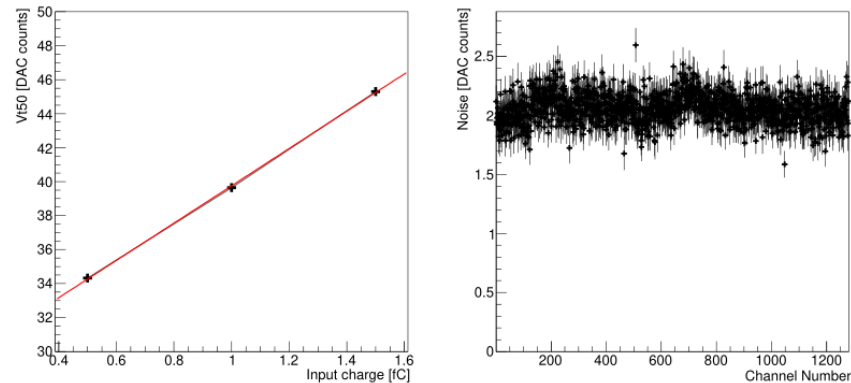
The 50% occupancy point indicates the threshold value, which corresponds to the injected charge after amplification, and the width characterizes the noise.

From the 50% points we generate the response curve which represent the shift in response as a function of increasing injected charge, which is fitted to a straight line.

The gain is taken as the slope of the fit.
 $\text{Gain} = (\text{response}) / (\text{input charge})$.



(a) S-curve obtained from a threshold scan of a readout channel (b) First derivative of an S-curve with Vt50 and noise.



(c) Gain of individual readout channel, (d) Noise of channels from all ASICs on one hybrid (about 400 ENC).